

MOS FET POWER AMPLIFIER

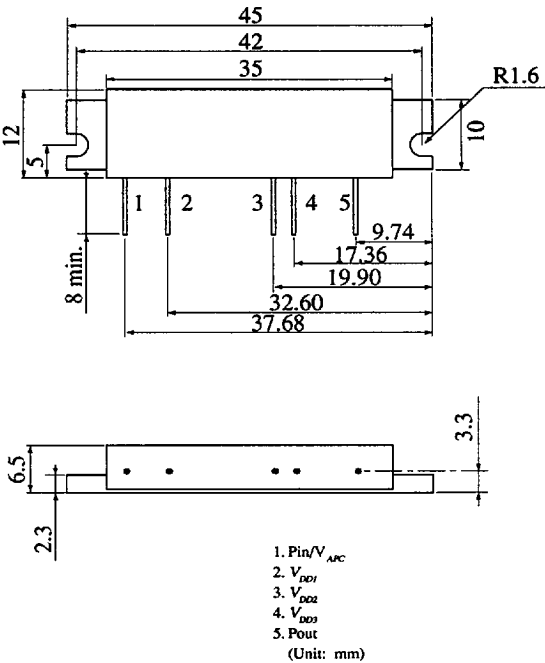
E-TACS Band 872-905 MHz

FEATURES

- Small Package 12 × 45 × 6.5 mm³
- Low Voltage Operation 6V
- Low Power Control Current 300μA
- Good Stability of Load Change Load VSWR ≥ 20

ABSOLUTE MAXIMUM RATINGS (Ta = 25°C)

Item	Symbol	Rating	Unit
Supply Voltage	V_{DD}	12	V
Supply Current	I_{DD}	2	A
APC Voltage	V_{APC}	± 8	V
Input Power	P_{in}	20	mW
Operating Case Temperature	$T_{C(op)}$	-30 ~ +100	°C
Storage Temperature	T_{stg}	-30 ~ +100	°C

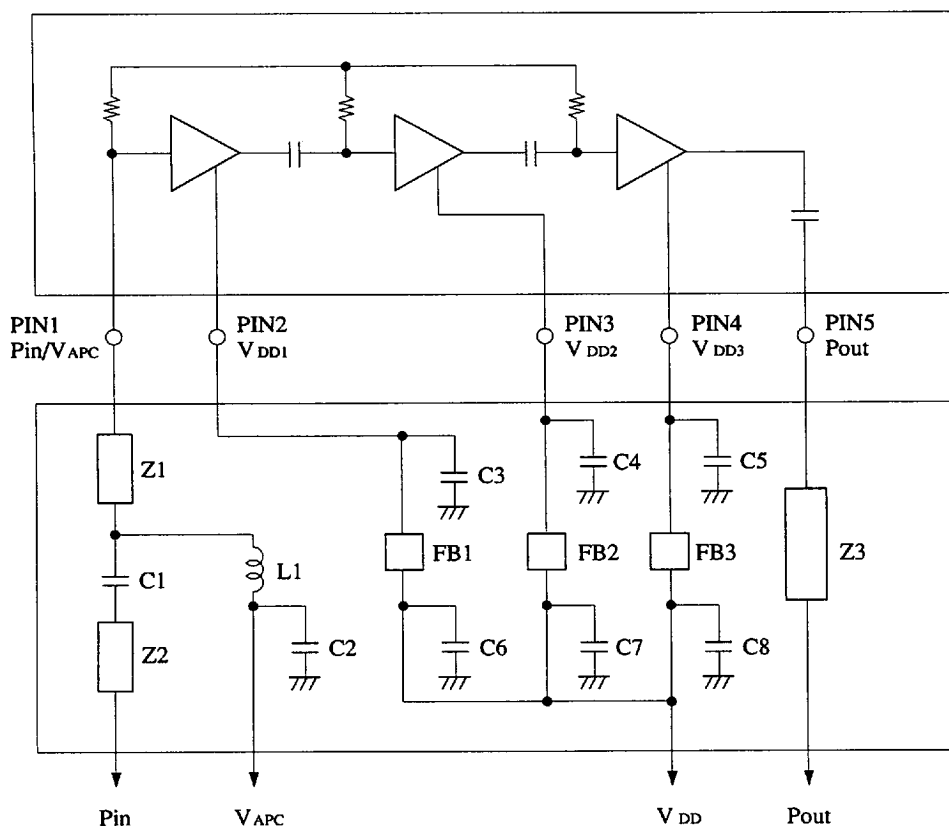


ELECTRICAL CHARACTERISTICS (Ta = 25°C)

Item	Symbol	Test Condition	min.	typ.	max.	Unit
Drain Cutoff Current	I_{DS}	$V_{DD1} = V_{DD2} = V_{DD3} = 12V, V_{APC} = 0V$	—	—	100	μA
Total Efficiency	η_r	$f = 872, 905MHz,$ $P_{in} = 1mW,$	35	40	—	%
2nd Harmonic Distortion	2nd H. D.	$V_{DD1} = V_{DD2} = V_{DD3} = 6V,$	—	-40	-30	dB
3rd Harmonic Distortion	3rd H. D.	$P_{out} = 1.2W$ (at APC Control), $Z_{in} = Z_{out} = 50\Omega$	—	-50	-30	dB
Input VSWR	VSWR (in)		—	1.8	3	—
Output VSWR	VSWR (out)		—	2	—	—
Stability	—	$V_{DD1} = V_{DD2} = V_{DD3} = 6V, P_{in} = 1mW,$ $f = 872MHz, R_s = 50\Omega,$ $P_{out} = 1.2W$ (at APC Control) Output VSWR = 20 All Phases, $t = 20sec$	No Parastic Oscillation			—

HITACHI/(OPTOELECTRONICS)

■TEST SYSTEM DIAGRAM



C1=0.02 μ F CERAMIC CHIP

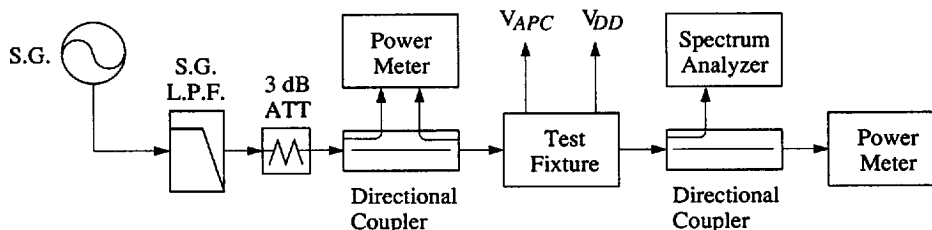
C2, C3, C4, C5=0.01 μ F CERAMIC CHIP

C6, C7, C8=10 μ F TANTALUM

L1=RFC 1mm ϕ , 15turns

FB=FERRITE BEAD BLO1RN1-A62-001(MURATA) or equivalent

Z1, Z2, Z3=50 Ω MICROSTRIP LINE

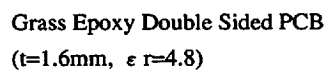


Output power Pout is defined at the root point of the module output pin Pout.

The coefficient of output power loss in the PCB output line Z3 is showed below.

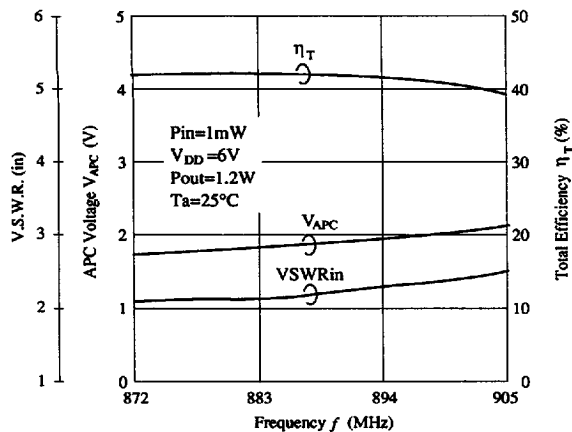
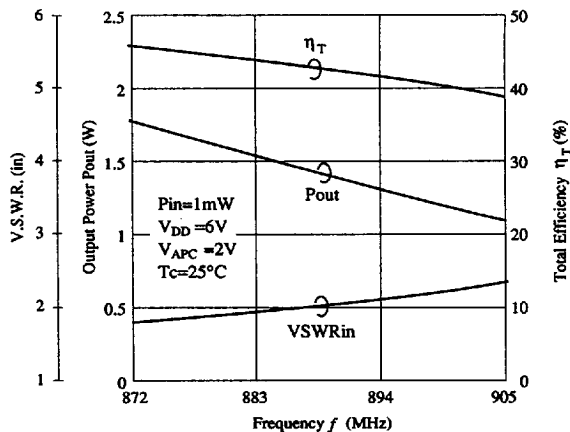
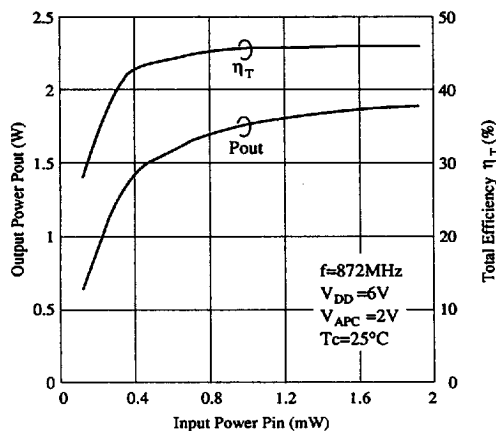
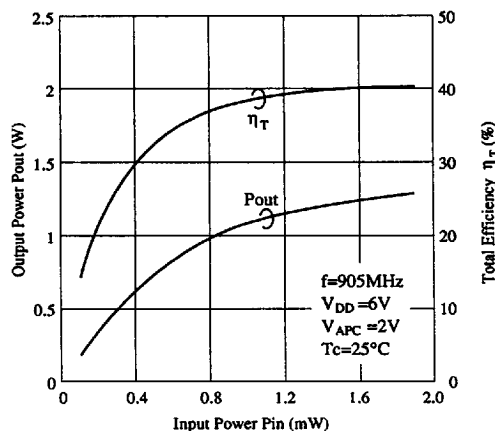
$$1/(S_{z1})^2=1/(0.9805)^2=1.04$$

■TEST FIXTURE PATTERN



UNIT : mm

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VSWR, V_{APC} , η_T VS. FREQUENCY

VSWR, P_{out} , η_T VS. FREQUENCY

 P_{out} , η_T VS. P_{in}

 P_{out} , η_T VS. P_{in}


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